



SLOVENSKI STANDARD SIST EN 62024-1:2008

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High frequency inductive components - Electrical characteristics and measuring methods
- Part 1: Nanohenry range chip inductor (IEC 62024-1:2008)

Induktive Hochfrequenz-Bauelemente - Elektrische Eigenschaften und Messmethoden -
Teil 1: Chipinduktivitäten im Nanohenry-Bereich (IEC 62024-1:2008)

Composants inductifs à haute fréquence - Caractéristiques électriques et méthodes de
mesure - Partie 1: Inductance à puce de l'ordre du nanohenry (CEI 62024-1:2008)

Ta slovenski standard je istoveten z: EN 62024-1:2008

ICS:

29.100.10 Magnetne komponente Magnetic components

SIST EN 62024-1:2008 en

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English version

**High frequency inductive components -
Electrical characteristics and measuring methods -
Part 1: Nanohenry range chip inductor
(IEC 62024-1:2008)**

Composants inductifs à haute fréquence -
Caractéristiques électriques
et méthodes de mesure -
Partie 1: Inductance à puce
de l'ordre du nanohenry
(CEI 62024-1:2008)

Induktive Hochfrequenz-Bauelemente -
Elektrische Eigenschaften
und Messmethoden -
Teil 1: Chipinduktivitäten
im Nanohenry-Bereich
(IEC 62024-1:2008)

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This European Standard was approved by CENELEC on 2008-03-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in two official versions (English and German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 51/908/FDIS, future edition 2 of IEC 62024-1, prepared by IEC TC 51, Magnetic components and ferrite materials, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62024-1 on 2008-03-01.

This European Standard supersedes EN 62024-1:2002.

EN 62024-1:2008 includes the following significant technical changes with respect to EN 62024-1:2002:

- size 0402 added in Table 1 and Table 2;
- contents of 4.4 reviewed for easier understanding;
- errors in 3.1.4.2 corrected.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2008-12-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2011-03-01

Annex ZA has been added by CENELEC.

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Endorsement notice

[SIST EN 62024-1:2008](#)

The text of the International Standard IEC 62024-1:2008 was approved by CENELEC as a European Standard without any modification. [425e7808351a/sist-en-62024-1-2008](#)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61249-2-7	- ¹⁾	Materials for printed boards and other interconnecting structures - Part 2-7: Reinforced base materials, clad and unclad - Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test) copper-clad	EN 61249-2-7 + corr. September	2002 ²⁾ 2005
ISO 6353-3	- ¹⁾	Reagents for chemical analysis - Part 3: Specifications - Second series	-	-
ISO 9453	- ¹⁾	Soft solder alloys - Chemical compositions and forms	-	-

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¹⁾ Undated reference.

²⁾ Valid edition at date of issue.

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INTERNATIONAL STANDARD

High frequency inductive components – Electrical characteristics and measuring methods –
Part 1: Nanohenry range chip inductor

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**HIGH FREQUENCY INDUCTIVE COMPONENTS –
ELECTRICAL CHARACTERISTICS AND MEASURING METHODS –****Part 1: Nanohenry range chip inductor**

FOREWORD

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International Standard IEC 62024-1 has been prepared by IEC technical committee 51: Magnetic components and ferrite materials.

This second edition cancels and replaces the first edition published in 2002. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) sizes 0402 added in Table 1 and Table 2;
- b) contents of 4.4 reviewed for easier understanding;
- c) correct errors in 3.1.4.2.

The text of this standard is based on the following documents:

FDIS	Report on voting
51/908/FDIS	51/915/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62024 series, published under the general title *High frequency inductive components – Electrical characteristics and measuring methods*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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